

**International Journal of Current
Microbiology and Applied Sciences
(IJCMAS) NAAS RATING-5.38, ICV-95.39**
ISSN: 2319-7692 (Print) ISSN 2319-7706 (Online)

An International, Monthly, Online, Free Access, Peer Reviewed,
Indexed, fast track Scientific Research Journal

Certificate of Publication

This is to certify that the following article reviewed by editorial board and published in International Journal of Current Microbiology and Applied Sciences (IJCMAS) ISSN: 2319-7692 (Print) ISSN 2319-7706 (Online).

Int.J.Curr.Microbiol.App.Sci.2018.7.(7):937-945

<https://doi.org/10.20546/ijcmas.2018.707.113>

Studies on Correlation and Path Analysis for Spot Blotch Disease Resistance and Yield Parameters in F2 Segregating Population of Durum Wheat (*Triticum durum* L.)

C.K. Chethana¹, V. Rudranaik^{1*}, S.A. Desai², S.S. Biradar¹, Y. Narendra Kadoo³, I.K. Kalappanavar⁴ and B.N. Aravindkumar⁵

¹AICRP on Wheat, Main Agricultural Research Station, University of Agricultural Sciences Dharwad - 580 005, Karnataka, India

²Protection of Plant Varieties and Farmer's Right Authority (PPV & FRA), PUSA, NewDelhi-110012, India)

³Biochemical Sciences Division, CSIR-National Chemical Laboratory, Pune, Maharashtra, India

⁴Department of Plant Pathology



Dr. M. Prakash
Editor-in-chief

International Journal of Current Microbiology and Applied Sciences

www.ijcmas.com

www.excellentpublishers.com



© International Journal of Current Microbiology and Applied
Sciences (IJCMAS)

www.excellentpublishers.com www.ijcmas.com